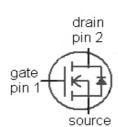


# **OptiMOS**(TM)3 Power-Transistor

#### **Features**

- Ideal for high frequency switching and sync. rec.
- Optimized technology for DC/DC converters
- Excellent gate charge x R DS(on) product (FOM)
- N-channel, logic level
- 100% avalanche tested
- Pb-free plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target applications

Туре	IPD220N06L3 G
	2 (tab)
Package	PG-TO-252-3
Marking	220N06L



pin 3

# **Maximum ratings,** at $T_j$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C	30	А
		T <sub>C</sub> =100 °C	21	
Pulsed drain current <sup>2)</sup>	/ <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	120	
Avalanche energy, single pulse <sup>3)</sup>	E <sub>AS</sub>	$I_{\rm D}$ =20 A, $R_{\rm GS}$ =25 $\Omega$	13	mJ
Gate source voltage	V <sub>GS</sub>		±20	V
Power dissipation	P <sub>tot</sub>	T <sub>C</sub> =25 °C	36	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

<sup>1)</sup>J-STD20 and JESD22

# **Product Summary**

V <sub>DS</sub>	60	٧
R <sub>DS(on),max</sub>	22	mΩ
I <sub>D</sub>	30	Α



 $<sup>^{2)}</sup>$  See figure 3 for more detailed information

<sup>&</sup>lt;sup>3)</sup> See figure 13 for more detailed information



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	R <sub>thJC</sub>		-	-	4.2	K/W
Thermal resistance,	$R_{\mathrm{thJA}}$	minimal footprint	-	-	62	
junction - ambient		6 cm² cooling area <sup>4)</sup>	-	-	40	

# **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

#### Static characteristics

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	60	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 11  \mu {\rm A}$	1.2	1.7	2.2	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =60 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C	1	0.1	1	μA
		V <sub>DS</sub> =60 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	1	10	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	1	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10 V, I <sub>D</sub> =30 A	-	17.8	22.0	mΩ
		V <sub>GS</sub> =4.5 V, I <sub>D</sub> =15 A	-	27.4	39.8	
Gate resistance	R <sub>G</sub>		-	0.9	-	Ω
Transconductance	$g_{ ext{fs}}$	V <sub>DS</sub>  >2 I <sub>D</sub>  R <sub>DS(on)max</sub> , I <sub>D</sub> =30 A	16	32	-	s

 $<sup>^{4)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70  $\mu m$  thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol	Symbol Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss		-	1200	1600	pF
Output capacitance	C <sub>oss</sub>	$V_{GS}$ =0 V, $V_{DS}$ =30 V, f=1 MHz	-	270	360	1
Reverse transfer capacitance	C <sub>rss</sub>	]	_	16	-	1
Turn-on delay time	t <sub>d(on)</sub>		_	9	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =30 V, V <sub>GS</sub> =10 V,	-	3	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =30 A, $R_{\rm G}$ =3 $\Omega$	-	19	-	
Fall time	t <sub>f</sub>		-	3	-	
Gate Charge Characteristics <sup>5)</sup>		<u>,                                      </u>				
Gate to source charge	Q <sub>gs</sub>		-	5	-	nC
Gate to drain charge	$Q_{gd}$	.,	-	2	-	
Switching charge	$Q_{sw}$	V <sub>DD</sub> =30 V, / <sub>D</sub> =30 A, V <sub>GS</sub> =0 to 4.5 V	-	5	-	_
Gate charge total	$Q_g$		-	7	10	
Gate plateau voltage	V <sub>plateau</sub>		ı	4.1	ı	٧
Output charge	Q oss	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =0 V	ı	13	17	nC
Reverse Diode						
Diode continous forward current	Is	T 05 %0	-	-	30	Α
Diode pulse current	/ <sub>S,pulse</sub>	T <sub>C</sub> =25 °C	-	-	120	1
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =30 A, T <sub>j</sub> =25 °C	-	1.0	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =30 V, / <sub>F</sub> =30A,	-	27	-	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i</i> <sub>F</sub> /d <i>t</i> =100 A/μs	_	23	-	nC

<sup>&</sup>lt;sup>5)</sup> See figure 16 for gate charge parameter definition

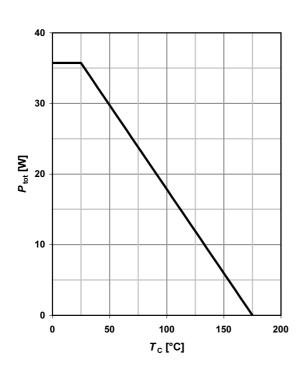


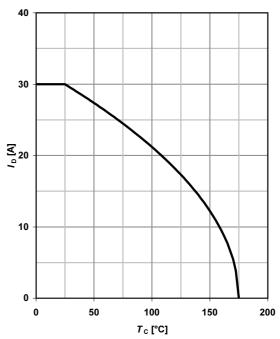
### 1 Power dissipation

# $P_{tot}$ =f( $T_{C}$ )

### 2 Drain current

$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$





# 3 Safe operating area

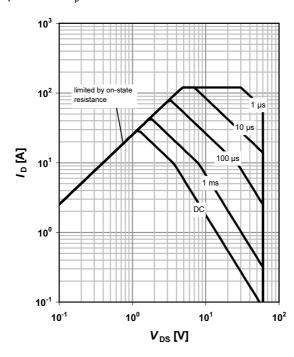
$$I_D$$
=f( $V_{DS}$ );  $T_C$ =25 °C;  $D$ =0

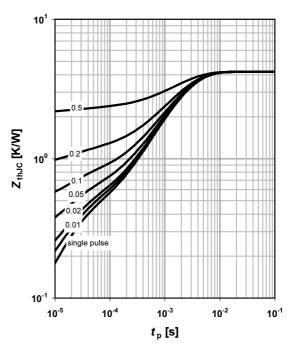
parameter:  $t_p$ 

# 4 Max. transient thermal impedance

$$Z_{thJC}$$
=f( $t_p$ )

parameter:  $D = t_p/T$ 



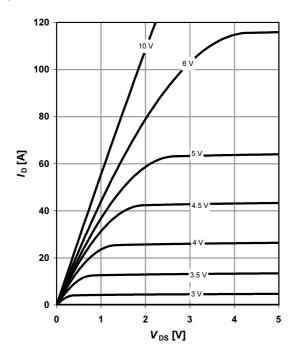




### 5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C$ 

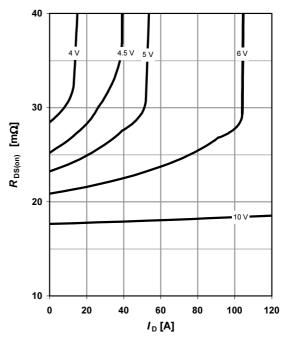
parameter:  $V_{\rm GS}$ 



# 6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =25 °C

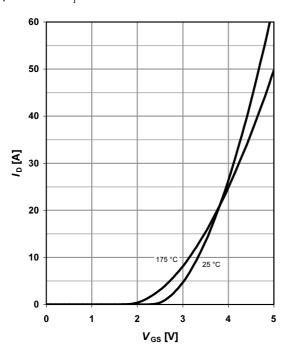
parameter: V<sub>GS</sub>



# 7 Typ. transfer characteristics

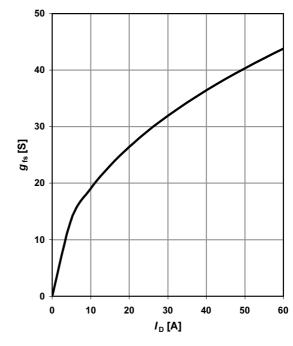
 $I_D = f(V_{GS}); |V_{DS}| > 2|I_D|R_{DS(on)max}$ 

parameter:  $T_{\rm j}$ 



# 8 Typ. forward transconductance

$$g_{fs}$$
=f( $I_D$ );  $T_j$ =25 °C





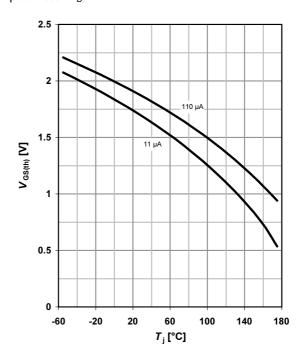
#### 9 Drain-source on-state resistance

 $R_{DS(on)}$ =f( $T_j$ );  $I_D$ =30 A;  $V_{GS}$ =10 V

# 50 45 40 35 30 R<sub>DS(on)</sub> [mΩ] 25 20 15 10 5 0 -60 -20 20 100 140 180 *T*<sub>j</sub> [°C]

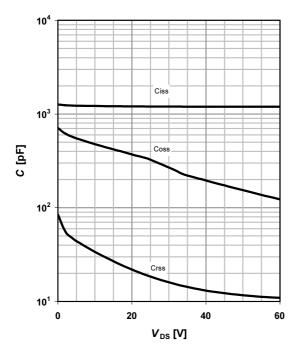
# 10 Typ. gate threshold voltage

 $V_{\rm GS(th)}$ =f( $T_{\rm j}$ );  $V_{\rm GS}$ = $V_{\rm DS}$ parameter:  $I_{\rm D}$ 



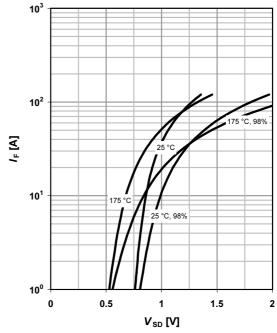
# 11 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 



### 12 Forward characteristics of reverse diode

 $I_{F}$ =f( $V_{SD}$ )
parameter:  $T_{j}$ 

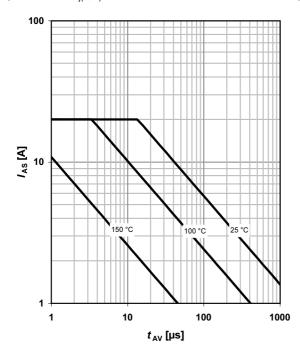




#### 13 Avalanche characteristics

 $I_{AS}$ =f( $t_{AV}$ );  $R_{GS}$ =25  $\Omega$ 

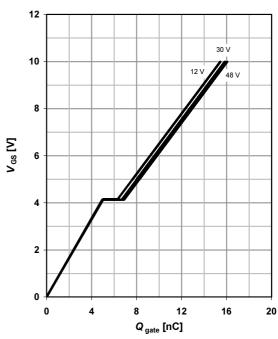
parameter:  $T_{j(start)}$ 



# 14 Typ. gate charge

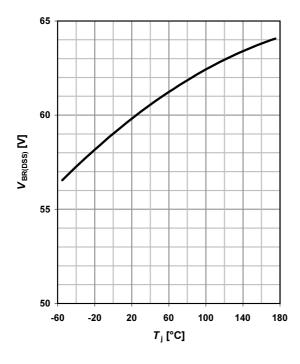
 $V_{\rm GS}$ =f(Q<sub>gate</sub>);  $I_{\rm D}$ =30 A pulsed

parameter:  $V_{\rm DD}$ 

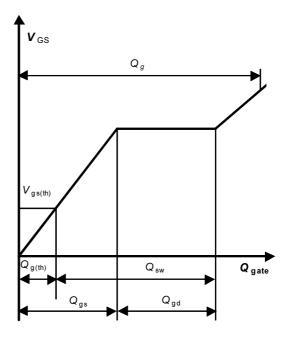


# 15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f( $T_j$ );  $I_D$ =1 mA

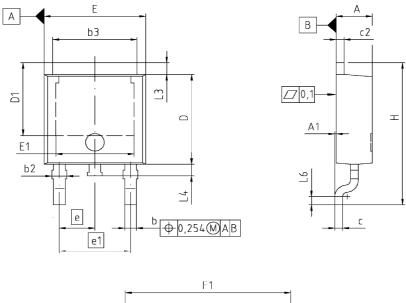


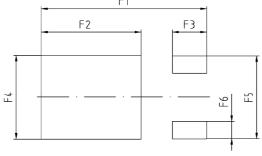
### 16 Gate charge waveforms



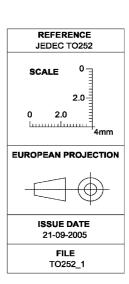


# PG-TO-252-3





DIM	MILLIN	METERS	INCHES			
DIM	MIN	MAX	MIN	MAX		
Α	2.159	2.413	0.085	0.095		
A1	0.000	0.150	0.000	0.006		
b	0.635	0.889	0.025	0.035		
b2	0.650	1.150	0.026	0.045		
b3	5.004	5.500	0.197	0.217		
C	0.457	0.580	0.018	0.023		
c2	0.460	0.980	0.018	0.039		
D	5.969	6.223	0.235	0.245		
D1	5.020	5.842	0.198	0.230		
Е	6.400	6.731	0.252	0.265		
E1	4.850	5.207	0.191	0.205		
е	2.	2.286		0.090		
e1	4.	572	0.	0.180		
N		3	3			
Н	9.400	10.480	0.370	0.413		
L3	0.900	1.143	0.035	0.045		
L4	0.584	0.950	0.023	0.037		
L6	0.510	0.686	0.020	0.027		
F1	10.500	10.700	0.413	0.421		
F2	6.300	6.500	0.248	0.256		
F3	2.100	2.300	0.083	0.091		
F4	5.700	5.900	0.224	0.232		
F5	5.660	5.860	0.222	0.231		
F6	1.100	1.300	0.043	0.051		





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